**Amendments to the Claims:**

This listing of claims will replace all prior versions, and listings, of claims in the application.

**Listing of Claims:**

Claims 1-33 (Canceled)

Claim 34 (Currently amended): A test head assembly comprising:

a probe card;

a contactor; ~~and~~

an interposer interconnecting said probe card and said contactor, said interposer comprising a first plurality of terminals disposed on a first surface of said interposer; and

~~wherein said interposer comprises~~ a first plurality of spring contacts, each of said first plurality of spring contacts comprising a base disposed on one of said first terminals and an integrally formed cantilevered beam extending away from [[a]] said first surface of said interposer, ~~and~~

wherein said beam is ~~contoured to affect~~ lithographically formed to have a shape comprising a contour that affects a deflection characteristic of said beam.

Claim 35 (Currently amended): The test head assembly of claim 34, wherein said ~~beam is contoured~~ contour is along a length of said beam.

Claim 36 (Currently amended): The test head assembly of claim 34, wherein, because of said contour, said beam ~~is contoured to increase a~~ has a greater bending moment [[of]] than said beam would have without said contour.

Claim 37 (Currently amended): The test head assembly of claim 34, wherein, because of said contour, said beam ~~is contoured to increase a~~ has a greater elastic range [[of]] than said beam would have without said contour.

Claim 38 (Currently amended): The test head assembly of claim 34, wherein, because of said contour, said beam ~~is contoured to increase a~~ has a greater elastic deflection ratio [[of]] than said beam would have without said contour.

Claim 39 (Currently amended): The test head assembly of claim 34, wherein, because of said contour, said beam ~~is contoured to increase an~~ has a greater area moment of inertia [[of]] than said beam would have without said contour.

Claim 40 (Currently amended): The test head assembly of claim 34, wherein, because of said contour, said beam ~~is contoured to stiffen~~ is stiffer than said beam would be without said contour.

Claim 41 (Previously presented): The test head assembly of claim 34, wherein said beam is corrugated.

Claim 42 (Currently amended): The test head assembly of claim 34, wherein said ~~beam is contoured~~ contour is along a cross-sectional width ~~thereof~~ of said beam.

Claim 43 (Previously presented): The test head assembly of claim 42, wherein said cross-sectional width is "V" shaped.

Claim 44 (Previously presented): The test head assembly of claim 42, wherein said cross-sectional width comprises a rib.

Claim 45 (Previously presented): The test head assembly of claim 34, wherein said beam is serpentine shaped.

Claim 46 (Currently amended): The test head assembly of claim 34, wherein:

said interposer further comprises a second plurality of terminals disposed on a second surface of said interposer,

said test head assembly further comprises a second plurality of spring contacts, each of said second plurality of spring contacts comprising a ~~contoured~~ base disposed on one of said second terminals and a lithographically formed, contoured, cantilevered beam extending away from [[a]] said second surface of said interposer, and

said contour of said beam affects a deflection characteristic of said beam.

Claims 47-50 (Canceled)

Claim 51 (Currently amended): A test head assembly comprising:

a probe card;

a contactor; and

a first plurality of spring contacts interconnecting said probe card and said contactor,

wherein each of said first plurality of spring contacts comprises a lithographically formed beam, and ~~contoured to affect~~

a shape of said beam comprises a contour that affects a deflection characteristic of said beam.

Claim 52 (Currently amended): The test head assembly of claim 51, wherein said ~~beam is contoured~~ contour is along a length of said beam.

Claim 53 (Currently amended): The test head assembly of claim 51, wherein, because of said contour, said beam ~~is contoured to increase a~~ has a greater bending moment [[of]] than said beam would have without said contour.

Claim 54 (Currently amended): The test head assembly of claim 51, wherein, because of said contour, said beam ~~is contoured to increase a~~ has a greater elastic range [[of]] than said beam would have without said contour.

Claim 55 (Currently amended): The test head assembly of claim 51, wherein, because of said contour, said beam ~~is contoured to increase a~~ has a greater elastic deflection ratio [[of]] than said beam would have without said contour.

Claim 56 (Currently amended): The test head assembly of claim 51, wherein, because of said contour, said beam ~~is contoured to increase an~~ has a greater area moment of inertia [[of]] than said beam would have without said contour.

Claim 57 (Currently amended): The test head assembly of claim 51, wherein, because of said contour, said beam ~~is contoured to stiffen~~ is stiffer than said beam would be without said contour.

Claim 58 (Previously presented): The test head assembly of claim 51, wherein said beam is corrugated.

Claim 59 (Currently amended): The test head assembly of claim 51, wherein said ~~beam is contoured~~ contour is along a cross-sectional width ~~thereof~~ of said beam.

Claim 60 (Previously presented): The test head assembly of claim 59, wherein said cross-sectional width is "V" shaped.

Claim 61 (Previously presented): The test head assembly of claim 59, wherein said cross-sectional width is "U" shaped.

Claim 62 (Previously presented): The test head assembly of claim 59, wherein said cross-sectional width comprises a rib.

Claim 63 (Previously presented): The test head assembly of claim 51, wherein said beam is serpentine shaped.

Claim 64 (Previously presented): The test head assembly of claim 51 further comprising a second plurality of spring contacts disposed on said contactor to contact an electronic device to be tested, wherein each of said second plurality of spring contacts comprising a contoured beam.

Claims 65-68 (Canceled)

Claim 69 (Withdrawn): The test head assembly of claim 34, wherein each of said spring contacts comprises a plurality of beams.

Claim 70 (Withdrawn): The test head assembly of claim 51, wherein each of said spring contacts comprises a plurality of beams.

Claim 71 (Previously presented): The test head assembly of claim 42, wherein said cross-sectional width is "U" shaped."

Claim 72 (New): The test head assembly of claim 34, wherein:

each of said first spring contacts comprises a first material and a seed material, and said first material is deposited onto said seed material.

Claim 73 (New): The test head assembly of claim 51, wherein:

each of said first spring contacts comprises a first material and a seed material, and said first material is deposited onto said seed material.